



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of:

WANG YUEH, ET AL.

Application No.: 10/687,288

Filed: October 15, 2003

For: **METHODS AND COMPOSITIONS FOR
REDUCING LINE WIDE ROUGHNESS**

Art Group: 1756

Examiner: Daborah Chacko Davis

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97

Commissioner for Patents
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Alexandria, VA 22313-1450

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The submission of this Information Disclosure Statement is not to be construed as a representation that a search has been made in the subject application and is not to be construed as an admission that the information cited in this statement is material to patentability.

Please charge any fees due to Deposit Account 02-2666. A duplicate copy of the Fee Transmittal (PTO/SB/17) is enclosed for this purpose.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP

Date: August 10, 2006

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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of

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Complete if Known

Application Number	10/687,288
Filing Date	October 15, 2003
First Named Inventor	Wang Yueh
Art Unit	1756
Examiner Name	Daborah Chacko Davis
Attorney Docket Number	42P17301

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		LAMMERS, DAVID, "Euro, Japan go to extremes for EUV," EE Times, 10/18/2002, 6 pages	
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		MEDEIROS, D.R., ET AL., "Recent progress in electron-beam resists for advanced mask-making," IBM J. RES. & DEV. vol 45, no. 5, 09/2001, pps. 639-650	
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		LINTON, T., ET AL., "Determination of the Line Edge Roughness Specification for 34 nm Devices," TCAD Division, Intel Corporation, 2002 IEEE, pps. 303-306	
		STEWART, MICHAEL D., ET AL., "Diffusion Induced Line Edge Roughness," Advances in Resist Technology and Processing XX, Proceedings of SPIE Vol. 5039, 2003, pps. 115-122	

Examiner
SignatureDate
Considered

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication.

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